- Center-Pin $V_{C C}$ and GND Configurations Minimize High-Speed Switching Noise
- EPICTM (Enhanced-Performance Implanted CMOS) 1- $\mu \mathrm{m}$ Process
- 500-mA Typical Latch-Up Immunity at $125^{\circ} \mathrm{C}$
- Package Options Include Plastic Small-Outline (D) and Thin Shrink Small-Outline (PW) Packages, and Standard Plastic 300-mil DIPs (N)

D, N, OR PW PACKAGE
(TOP VIEW)


## description

This device contains two independent positive-edge-triggered D-type flip-flops. A low level at the preset ( $\overline{\mathrm{PRE}})$ or clear ( $\overline{\mathrm{CLR})}$ input sets or resets the outputs regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the data (D) input that meets the setup-time requirements are transferred to the outputs on the low-to-high transition of the clock (CLK) pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the D input may be changed without affecting the levels at the outputs.
The 74 AC 11074 is characterized for operation from $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$.
FUNCTION TABLE

| INPUTS |  |  |  | OUTPUT |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\overline{\text { PRE }}$ | $\overline{\text { CLR }}$ | CLK | D | Q | $\overline{\mathbf{Q}}$ |
| L | H | X | X | H | L |
| H | L | X | X | L | H |
| L | L | X | X | $\mathrm{H}^{\dagger}$ | $\mathrm{H}^{\dagger}$ |
| H | H | $\uparrow$ | H | H | L |
| H | H | $\uparrow$ | L | L | H |
| H | H | L | X | $\mathrm{Q}_{0}$ | $\overline{\mathrm{Q}}_{0}$ |

$\dagger$ This configuration is nonstable; that is, it does not persist when $\overline{\mathrm{PRE}}$ or $\overline{\mathrm{CLR}}$ returns to its inactive (high) level.

## logic symbol $\dagger$


$\dagger$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted) $\ddagger$


Input voltage range, $\mathrm{V}_{\mathrm{I}}$ (see Note 1) ................................................... -0.5 V to $\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$




Continuous current through $\mathrm{V}_{\mathrm{CC}}$ or GND ......................................................... $\pm 100 \mathrm{~mA}$
Maximum power dissipation at $\mathrm{T}_{\mathrm{A}}=55^{\circ} \mathrm{C}$ (in still air) (see Note 2): D package .................... 1.25 W
N package ...................... 1.1 W
PW package .................... 0.5 W

$\ddagger$ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed
2. The maximum package power dissipation is calculated using a junction temperature of $150^{\circ} \mathrm{C}$ and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

## recommended operating conditions

|  |  |  | MIN | NOM | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage |  | 3 | 5 | 5.5 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | High-level input voltage | $\mathrm{V}_{\mathrm{CC}}=3 \mathrm{~V}$ | 2.1 |  |  | V |
|  |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$ | 3.15 |  |  |  |
|  |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$ | 3.85 |  |  |  |
| VIL | Low-level input voltage | $\mathrm{V}_{\mathrm{CC}}=3 \mathrm{~V}$ |  |  | 0.9 | V |
|  |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$ |  |  | 1.35 |  |
|  |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$ |  |  | 1.65 |  |
| $\mathrm{V}_{1}$ | Input voltage |  | 0 |  | $\mathrm{V}_{\mathrm{CC}}$ | V |
| $\mathrm{V}_{\mathrm{O}}$ | Output voltage |  | 0 |  | $\mathrm{V}_{\mathrm{CC}}$ | V |
| IOH | High-level output current | $\mathrm{V}_{\mathrm{CC}}=3 \mathrm{~V}$ |  |  | -4 | mA |
|  |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$ |  |  | -24 |  |
|  |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$ |  |  | -24 |  |
| IOL | Low-level output current | $\mathrm{V}_{\mathrm{CC}}=3 \mathrm{~V}$ |  |  | 12 | mA |
|  |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$ |  |  | 24 |  |
|  |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$ |  |  | 24 |  |
| $\Delta t / \Delta v$ | Input transition rise or fall rate |  | 0 |  | 10 | ns/V |
| $\mathrm{T}_{\text {A }}$ | Operating free-air temperature |  | -40 |  | 85 | ${ }^{\circ} \mathrm{C}$ |

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | TEST CONDITIONS |  | Vcc | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  |  | MIN | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP | MAX |  |  |  |
| $\mathrm{V}_{\mathrm{OH}}$ | $\mathrm{IOH}=-50 \mu \mathrm{~A}$ |  |  | 3 V | 2.9 |  |  | 2.9 |  | V |
|  |  |  | 4.5 V | 4.4 |  |  | 4.4 |  |  |  |
|  |  |  | 5.5 V | 5.4 |  |  | 5.4 |  |  |  |
|  | $\mathrm{IOH}=-4 \mathrm{~mA}$ |  | 3 V | 2.58 |  |  | 2.48 |  |  |  |
|  | $\mathrm{IOH}=-24 \mathrm{~mA}$ |  | 4.5 V | 3.94 |  |  | 3.8 |  |  |  |
|  |  |  | 5.5 V | 4.94 |  |  | 4.8 |  |  |  |
|  | $\mathrm{l}^{\mathrm{OH}}=-75 \mathrm{~mA} \dagger$ |  | 5.5 V |  |  |  | 3.85 |  |  |  |
| VOL | $\mathrm{l} \mathrm{OL}=50 \mu \mathrm{~A}$ |  | 3 V |  |  | 0.1 |  | 0.1 | V |  |
|  |  |  | 4.5 V |  |  | 0.1 |  | 0.1 |  |  |
|  |  |  | 5.5 V |  |  | 0.1 |  | 0.1 |  |  |
|  | $\mathrm{l} \mathrm{OL}=12 \mathrm{~mA}$ |  | 3 V |  |  | 0.36 |  | 0.44 |  |  |
|  | $\mathrm{IOL}=24 \mathrm{~mA}$ |  | 4.5 V |  |  | 0.36 |  | 0.44 |  |  |
|  |  |  | 5.5 V |  |  | 0.36 |  | 0.44 |  |  |
|  | $\mathrm{IOL}=75 \mathrm{~mA} \dagger$ |  | 5.5 V |  |  |  |  | 1.65 |  |  |
| 1 | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{CC}}$ or GND |  | 5.5 V |  |  | $\pm 0.1$ |  | $\pm 1$ | $\mu \mathrm{A}$ |  |
| ICC | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\text {CC }}$ or GND, | $\mathrm{I}=0$ | 5.5 V |  |  | 4 |  | 40 | $\mu \mathrm{A}$ |  |
| $\mathrm{C}_{\mathrm{i}}$ | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\text {CC }}$ or GND |  | 5 V |  | 3.5 |  |  |  | pF |  |

[^0]timing requirements over recommended operating free-air temperature range, $\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V} \pm 0.3 \mathrm{~V}$ (see Figure 1)

timing requirements over recommended operating free-air temperature range, $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V} \pm 0.5 \mathrm{~V}$ (see Figure 1)

|  |  |  | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  | MIN | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | MAX |  |  |  |
| $\mathrm{f}_{\text {clock }}$ | Clock frequency |  | 0 | 125 | 0 | 125 | MHz |
| ${ }^{\text {w }}$ w | Pulse duration | $\overline{\text { PRE or } \overline{C L R}}$ low | 4 |  | 4 |  | ns |
|  |  | CLK low or CLK high | 4 |  | 4 |  |  |
| $\mathrm{t}_{\text {su }}$ | Setup time before CLK $\uparrow$ | Data high or low | 3.5 |  | 3.5 |  | ns |
|  |  | $\overline{\text { PRE }}$ or $\overline{\mathrm{CLR}}$ inactive | 1 |  | 1 |  |  |
| th | Hold time after CLK $\uparrow$ |  | 0 |  | 0 |  | ns |

switching characteristics over recommended operating free-air temperature range, $\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V} \pm 0.3 \mathrm{~V}$ (unless otherwise noted) (see Figure 1)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  |  | MIN | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP | MAX |  |  |  |
| $\mathrm{f}_{\text {max }}$ |  |  | 100 | 125 |  | 100 |  | MHz |
| tPLH | $\overline{\text { PRE }}$ or $\overline{\mathrm{CLR}}$ | Q or $\overline{\mathrm{Q}}$ | 1.5 | 5.8 | 9.3 | 1.5 | 10 | ns |
| tphL |  |  | 1.5 | 6.5 | 11.4 | 1.5 | 12.2 |  |
| tPLH | CLK | Q or $\overline{\mathrm{Q}}$ | 1.5 | 7.7 | 10.5 | 1.5 | 11.3 | ns |
| tPHL |  |  | 1.5 | 7.3 | 9.7 | 1.5 | 10.6 |  |

switching characteristics over recommended operating free-air temperature range, $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V} \pm 0.5 \mathrm{~V}$ (unless otherwise noted) (see Figure 1)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  |  | MIN | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP | MAX |  |  |  |
| $f_{\text {max }}$ |  |  | 125 | 150 |  | 125 |  | MHz |
| tPLH | $\overline{\text { PRE }}$ or $\overline{\mathrm{CLR}}$ | Q or $\overline{\mathrm{Q}}$ | 1.5 | 4.2 | 6.6 | 1.5 | 7.1 | ns |
| tPHL |  |  | 1.5 | 4.7 | 8.2 | 1.5 | 9 |  |
| tPLH | CLK | Q or $\overline{\mathrm{Q}}$ | 1.5 | 5.4 | 7.5 | 1.5 | 8.2 | ns |
| tPHL |  |  | 1.5 | 5 | 6.9 | 1.5 | 7.5 |  |

operating characteristics, $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$

| PARAMETER | TEST CONDITIONS | TYP | UNIT |  |
| :--- | :--- | :---: | :---: | :---: |
| $\mathrm{C}_{\mathrm{pd}}$ | Power dissipation capacitance | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}, \quad \mathrm{f}=1 \mathrm{MHz}$ | 30 | pF |

## PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT


VOLTAGE WAVEFORMS


NOTES: A
A. $C_{L}$ includes probe and jig capacitance.
B. All input pulses are supplied by generators having the following characteristics: $\mathrm{PRR} \leq 10 \mathrm{MHz}, \mathrm{Z}_{\mathrm{O}}=50 \Omega, \mathrm{t}_{\mathrm{r}}=3 \mathrm{~ns}, \mathrm{t}_{\mathrm{f}}=3 \mathrm{~ns}$.
C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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[^0]:    $\dagger$ Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms .

